

April 1988 Revised August 1999

74F30

8-Input NAND Gate

General Description

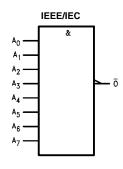
This device contains a single gate, which performs the logic NAND function.

Ordering Code:

Order Number	Package Number	Package Description					
74F30SC	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow					
74F30SJ	M14D	14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide					
74F30PC	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide					

Devices also available in Tape and Reel. Specify by appending the letter "X" to the ordering code.

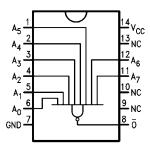
Logic Symbol



Unit Loading/Fan Out

Din Names	Description	U.L.	Input I _{IH} /I _{IL}		
riii Naiiles	Description	HIGH/LOW	Output I _{OH} /I _{OL}		
A ₀ -A ₇	Inputs	1.0/1.0	20 μA/-0.6 mA		
ō	Output	50/33.3	-1 mA/20 mA		

Connection Diagram



Function Table

	Inputs							
A ₀	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	ō
L	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Н
Х	L	Χ	X	Χ	Χ	X	X	Н
Х	X	L	X	Χ	Χ	Χ	X	Н
Х	X	Χ	L	Χ	Χ	X	X	Н
Х	Χ	X	Χ	L	Χ	Χ	Χ	Н
Х	Χ	X	Χ	Χ	L	Χ	Χ	Н
Х	Χ	X	Χ	Χ	Χ	L	Χ	Н
Х	Χ	Χ	Χ	Χ	Χ	Χ	L	Н
Н	Н	Н	Н	Н	Н	Н	Н	L

H = HIGH Voltage Level L = LOW Voltage Level

X = Immaterial

Absolute Maximum Ratings(Note 1)

-65°C to +150°C

-30 mA to +5.0 mA

-55°C to +125°C Ambient Temperature under Bias Junction Temperature under Bias -55°C to +150C V_{CC} Pin Potential to Ground Pin -0.5V to +7.0VInput Voltage (Note 2) -0.5V to +7.0V

Input Current (Note 2) Voltage Applied to Output

Storage Temperature

in HIGH State (with $V_{CC} = 0V$)

Standard Output -0.5V to V_{CC} 3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA)

Recommended Operating Conditions

Free Air Ambient Temperature 0°C to +70°C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

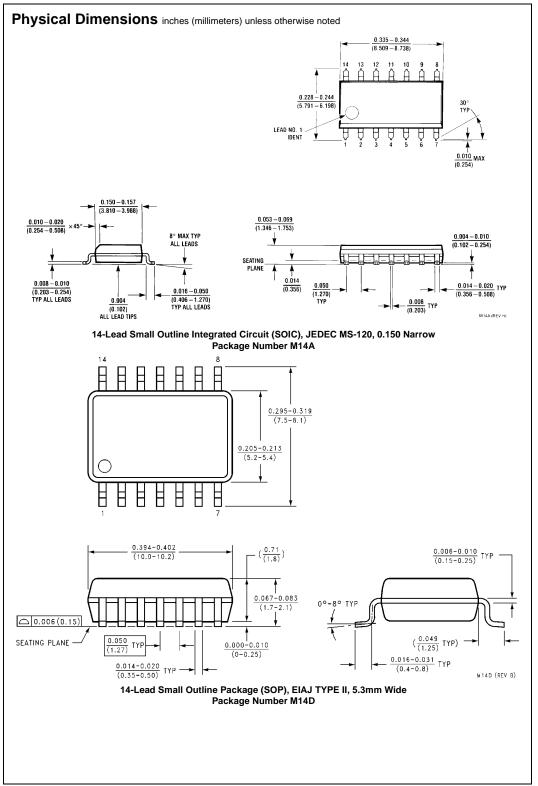
Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

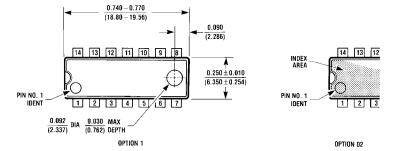
Symbol	mbol Parameter		Min	Тур	Max	Units	V _{cc}	Conditions	
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal	
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal	
V _{CD}	Input Clamp Diode Voltage				-1.2	V	Min	$I_{IN} = -18 \text{ mA}$	
V _{OH}	Output HIGH Voltage	10% V _{CC} 5% V _{CC}	2.5 2.7			V	Min	$I_{OH} = -1 \text{ mA}$ $I_{OH} = -1 \text{ mA}$	
V _{OL}	Output LOW Voltage	10% V _{CC}			0.5	V	Min	I _{OL} = 20 mA	
I _{IH}	Input HIGH Current				5.0	μА	Max	V _{IN} = 2.7V	
I _{BVI}	Input HIGH Current Breakdown Test				7.0	μА	Max	V _{IN} = 7.0V	
I _{CEX}	Output HIGH Leakage Current				50	μА	Max	$V_{OUT} = V_{CC}$	
V _{ID}	Input Leakage Test		4.75			V	0.0	$I_{ID} = 1.9 \mu A$ All Other Pins Grounded	
I _{OD}	Output Leakage Circuit Current				3.75	μА	0.0	V _{IOD} = 150 mV All Other Pins Grounded	
I _{IL}	Input LOW Current				-0.6	mA	Max	V _{IN} = 0.5V	
Ios	Output Short-Circuit Current		-60		-150	mA	Max	V _{OUT} = 0V	
I _{CCH}	Power Supply Current			0.5	1.5	mA	Max	V _O = HIGH	
I _{CCL}	Power Supply Current				4.5	mA	Max	$V_O = LOW$	

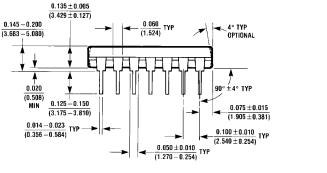
AC Electrical Characteristics

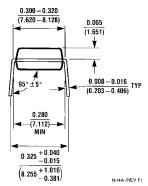
			$T_A = +25^{\circ}C$		$T_A = 0$ °C to +70°C			
Symbol	Parameter	$V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		Units	
		Min	Тур	Max	Min	Max		
t _{PLH}	Propagation Delay	1.0	3.7	5.0	1.0	5.5		
	A_n to \overline{O}	1.5	2.8	5.0	1.5	5.5	ns	



Physical Dimensions inches (millimeters) unless otherwise noted (Continued)







14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N14A

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